

Abstract

MD
4/26/04~~Integrated circuit with built-in module test~~

The invention relates to an integrated circuit (1), especially an ASIC, which consists of a multiplicity of logic gates (2). To perform an internal self test of the multiplicity of logic gates (2), a self-test circuit (3) is provided which exhibits a test pattern generator (4) and a test response analyzer (5). In addition, a test of an external circuit (14, 15) can be performed with the self-test circuit (3) built into the integrated circuit via an input/output circuit (7) provided in the integrated circuit.

MD
4/26/04~~Figure 1~~

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